

DESCRIPTION

These miniature surface mount MOSFETs utilize a high cell density trench process to provide low $R_{DS(on)}$ and to ensure minimal power loss and heat dissipation. Typical applications are DC-DC converters and power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

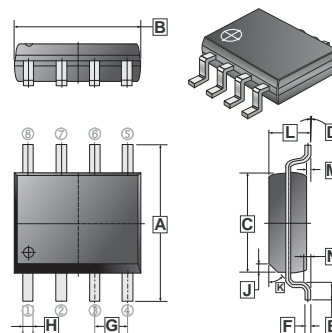
FEATURES

- Low $R_{DS(on)}$ provides higher efficiency and extends battery life.
- Low thermal impedance copper leadframe SOIC-8 saves board space.
- Fast switching speed.
- High performance trench technology.

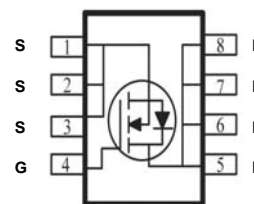
PACKAGE INFORMATION

| Package | MPQ | LeaderSize |
|---------|------|------------|
| SOP-8 | 2.5K | 13' inch |

SOP-8



| REF. | Millimeter | | REF. | Millimeter | |
|------|------------|------|------|------------|------|
| | Min. | Max. | | Min. | Max. |
| A | 5.80 | 6.20 | H | 0.35 | 0.49 |
| B | 4.80 | 5.00 | J | 0.375 REF. | |
| C | 3.80 | 4.00 | K | 45° | |
| D | 0° | 8° | L | 1.35 | 1.75 |
| E | 0.40 | 0.90 | M | 0.10 | 0.25 |
| F | 0.19 | 0.25 | N | 0.25 REF. | |
| G | 1.27 TYP. | | | | |



MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ unless otherwise specified)

| Parameter | Symbol | Ratings | Unit |
|--|--------------------------------|-----------|-----------------------------|
| Drain-Source Voltage | V_{DS} | 100 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current ¹ | $I_D @ T_A = 25^\circ\text{C}$ | 5.2 | A |
| | $I_D @ T_A = 70^\circ\text{C}$ | 3.9 | A |
| Pulsed Drain Current ² | I_{DM} | 50 | A |
| Continuous Source Current (Diode Conduction) ¹ | I_S | 2.3 | A |
| Total Power Dissipation ¹ | $P_D @ T_A = 25^\circ\text{C}$ | 3.1 | W |
| | $P_D @ T_A = 70^\circ\text{C}$ | 2.2 | W |
| Operating Junction & Storage Temperature Range | T_J, T_{STG} | -55 ~ 150 | $^\circ\text{C}$ |
| Thermal Resistance Ratings | | | |
| Thermal Resistance Junction-Case (Max.) ¹ $t \leq 5$ sec | $R_{\theta JC}$ | 25 | $^\circ\text{C} / \text{W}$ |
| Thermal Resistance Junction-ambient (Max.) ¹ $t \leq 5$ sec | $R_{\theta JA}$ | 50 | $^\circ\text{C} / \text{W}$ |

Notes

1. Surface Mounted on 1" x 1" FR4 Board.
2. Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise specified)

| Parameter | Symbol | Min. | Typ. | Max. | Unit | Test Conditions |
|---|--------------|------|------|-----------|---------------|--|
| Static | | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | 1 | - | - | V | $V_{DS} = V_{GS}, I_D = -250\mu\text{A}$ |
| Gate-Body Leakage Current | I_{GSS} | - | - | ± 100 | nA | $V_{DS} = 0\text{V}, V_{GS} = 20\text{V}$ |
| Zero Gate Voltage Drain Current | I_{DSS} | - | - | 1 | μA | $V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$ |
| | | - | - | 25 | μA | $V_{DS} = 80\text{V}, V_{GS} = 0\text{V}, T_J = 55^\circ\text{C}$ |
| On-State Drain Current ¹ | $I_{D(on)}$ | 20 | - | - | A | $V_{DS} = 5\text{V}, V_{GS} = 10\text{V}$ |
| Drain-Source On-Resistance ¹ | $R_{DS(ON)}$ | - | - | 78 | m Ω | $V_{GS} = 10\text{V}, I_D = 5.2\text{A}$ |
| | | - | - | 92 | | $V_{GS} = 4.5\text{V}, I_D = 4.8\text{A}$ |
| Forward Transconductance ¹ | g_{fs} | - | 40 | - | S | $V_{DS} = 15\text{V}, I_D = 5.2\text{A}$ |
| Diode Forward Voltage | V_{SD} | - | 0.7 | - | V | $I_S = 2.3\text{A}, V_{GS} = 0\text{V}$ |
| Dynamic ² | | | | | | |
| Total Gate Charge | Q_g | - | 12.5 | - | nC | $I_D = 5.2\text{A}$ $V_{DS} = 15\text{V}$ $V_{GS} = 4.5\text{V}$ |
| Gate-Source Charge | Q_{gs} | - | 2.6 | - | | |
| Gate-Drain("Miller") Charge | Q_{gd} | - | 4.6 | - | | |
| Switching | | | | | | |
| Turn-On Delay Time | $T_{d(on)}$ | - | 20 | - | nS | $V_{DD} = 25\text{V}$ $I_D = 1\text{A}$ $V_{GEN} = 10\text{V}$ $R_L = 25\Omega$ |
| Rise Time | T_r | - | 9 | - | | |
| Turn-Off Delay Time | $T_{d(off)}$ | - | 70 | - | | |
| Fall Time | T_f | - | 20 | - | | |

Notes

- Pulse test : $PW \leq 300\mu\text{s}$ duty cycle $\leq 2\%$.
- Guaranteed by design, not subject to production testing.